

# Deutsche Akkreditierungsstelle

## Annex to the Partial Accreditation Certificate D-PL-12095-01-02 according to DIN EN ISO/IEC 17025:2018

**Valid from:** 16.12.2024

**Date of issue:** 18.02.2025

This annex is a part of the accreditation certificate D-PL-12095-01-00.

Holder of partial accreditation certificate:

**Weidmüller Interface GmbH & Co. KG**  
**Klingenbergstraße 26, 32758 Detmold**

with the locations

**Weidmüller Interface GmbH & Co. KG**  
**Zentrallabor – Standort Detmold**  
**Orbker Straße 48, 32758 Detmold**

The testing laboratory meets the requirements of DIN EN ISO/IEC 17025:2018 to carry out the conformity assessment activities listed in this annex. The testing laboratory meets additional legal and normative requirements, if applicable, including those in relevant sectoral schemes, provided that these are explicitly confirmed below.

The management system requirements of DIN EN ISO/IEC 17025 are written in the language relevant to the operations of testing laboratories and they conform to the principles of DIN EN ISO 9001.

**Determination of dimensional/shape/positional deviations of components using optical and computer tomography (CT) 3D coordinate measuring machines.**

**Carrying out dimensional first article inspections on components using optical and computer tomography (CT) 3D coordinate measuring machines.**

*This certificate annex is only valid together with the written accreditation certificate and reflects the status as indicated by the date of issue. The current status of any given scope of accreditation can be found in the directory of accredited bodies maintained by Deutsche Akkreditierungsstelle GmbH at <https://www.dakks.de>.*

Abbreviations used: see last page

**Page 1 of 2**

**This document is a translation. The definitive version is the original German annex to the accreditation certificate.**

**Annex to the Partial Accreditation Certificate D-PL-12095-01-02**

LPV2313 2024-08      Carrying out geometric measurements on components using  
industrial computed tomography (ICT) and optical fringe light projection.

**Verwendete Abkürzungen:**

DIN      Deutsches Institut für Normung e.V. - German Institute for Standardization e.V.  
EN      Europäische Norm - European standard  
IEC      International Electrotechnical Commission – Internationale Elektrotechnische Kommission  
ISO      International Organization for Standardization – Internationale Organisation für Normung  
LPV      Laboratory test specification of Weidmüller Interface GmbH & Co. KG

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